



CAMCOR

Oregon's High-Tech Extension Service



Pacific Northwest Thin Film and Particle Workshop for High Tech Industry

Instruments:

Cameca SX50 with Bruker SDD
Cameca SX100 with Thermo SDD
FEI Quanta with Thermo SDD and HKL EBSD
FEI Helios dual beam
Zeiss Ultra 55
(Nabity Lithography)
FEI Titan Analytical TEM
IonToF TOF-SIMS
Thermo VG ESCALab XPS
Waters Q-TOF
Philips Auger, Bruker, Rigaku and Scintag XRDs

May 14th, 2009

- 8:30** Dave Johnson: Welcome and Introduction
- 8:40** Dave Johnson: *Using XRD to Characterize Thin Film Crystallinity and Thickness*
- 8:50** Steve Golledge: *Using XPS and TOF-SIMS to Characterize Thin Films and Particles*
- 9:05** Kurt Langworthy: *Using SEM, TEM and FIB to Characterize Particles*
- 9:20** John Donovan: *Using EPMA and EBSD to Characterize Thin Film Chemistry and Texture*
- 9:30** Janet Teshima: *The Nano-Network Vision-Collaborations between Industry, National Labs and Oregon Universities*
- 9:45** Dave Schut: *Voxtel: Applied Nanotechnologies Collaborations with CAMCOR and ONAMI*

10:00-10:30 Break

- 10:30** Jim Hutchison: *Nano-particle Characterization for Industry*
- 10:45** Peter Moeck: *Structural Fingerprinting of Nanocrystals in the Transmission Electron Microscope*
- 11:00** Janet Tate: *Transport and Optical Characterization of Thin Film Semiconductors and Dielectrics*
- 11:15** Sergei Rouvimov: *Application of TEM/HREM Methods to Failure Analysis and Materials Research in Academic and Industrial Environments: Challenges and Perspectives*
- 11:30** Mark Lonergan: *SunRISE - The Support Network for Research and Innovation in Solar Energy*
- 11:45** Doug Keszler: *Using X-ray and Electron-Beam Tools to Characterize and Pattern Oxide Materials*

12:00 - 1:00 Luncheon and Mixer

- 1:00** Dave Johnson: Invitation to Lab Demonstrations and Student Posters
- 1:15** Student Posters and Laboratory Tours/Demonstrations (*Graduate Students and CAMCOR Staff*)
- 3:00** Wrap up